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-	Application/Control No.	Applicant(s)/Patent under Reexamination	<del></del>
	09/823,581	CHEN ET AL.	
	Examiner	Art Unit	
	Scott L. Jarrett	3623	

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INT	INTERFERENCE SEARCHED		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST - EP, JP, US see attached search history	8/31/2006	SJ
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